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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

E·XFI

Product Status	Obsolete
Number of LABs/CLBs	1452
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	113
Number of Gates	24000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx16a-tq144

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General Description

Introduction

The Actel SX-A family of FPGAs offers a cost-effective, single-chip solution for low-power, high-performance designs. Fabricated on 0.22 μm / 0.25 μm CMOS antifuse technology and with the support of 2.5 V, 3.3 V and 5 V I/Os, the SX-A is a versatile platform to integrate designs while significantly reducing time-to-market.

SX-A Family Architecture

The SX-A family's device architecture provides a unique approach to module organization and chip routing that satisfies performance requirements and delivers the most optimal register/logic mix for a wide variety of applications.

Interconnection between these logic modules is achieved using Actel's patented metal-to-metal programmable antifuse interconnect elements (Figure 1-1). The antifuses are normally open circuit and, when programmed, form a permanent low-impedance connection.



Note: The A54SX72A device has four layers of metal with the antifuse between Metal 3 and Metal 4. The A54SX08A, A54SX16A, and A54SX32A devices have three layers of metal with the antifuse between Metal 2 and Metal 3.

Figure 1-1 • SX-A Family Interconnect Elements

Power-Up/Down and Hot Swapping

SX-A I/Os are configured to be hot-swappable, with the exception of 3.3 V PCI. During power-up/down (or partial up/down), all I/Os are tristated. V_{CCA} and V_{CCI} do not have to be stable during power-up/down, and can be powered up/down in any order. When the SX-A device is plugged into an electrically active system, the device will not degrade the reliability of or cause damage to the host system. The device's output pins are driven to a high impedance state until normal chip operating conditions

are reached. Table 1-4 summarizes the V_{CCA} voltage at which the I/Os behave according to the user's design for an SX-A device at room temperature for various ramp-up rates. The data reported assumes a linear ramp-up profile to 2.5 V. For more information on power-up and hot-swapping, refer to the application note, Actel SX-A and RT54SX-S Devices in Hot-Swap and Cold-Sparing Applications.

Function	Description
Input Buffer Threshold Selections	 5 V: PCI, TTL 3.3 V: PCI, LVTTL 2.5 V: LVCMOS2 (commercial only)
Flexible Output Driver	 5 V: PCI, TTL 3.3 V: PCI, LVTTL 2.5 V: LVCMOS2 (commercial only)
Output Buffer	 "Hot-Swap" Capability (3.3 V PCI is not hot swappable) I/O on an unpowered device does not sink current Can be used for "cold-sparing" Selectable on an individual I/O basis Individually selectable slew rate; high slew or low slew (The default is high slew rate). The slew is only affected on the falling edge of an output. Rising edges of outputs are not affected.
Power-Up	Individually selectable pull-ups and pull-downs during power-up (default is to power-up in tristate) Enables deterministic power-up of device V _{CCA} and V _{CCI} can be powered in any order

Table 1-2 • I/O Features

Table 1-3 • I/O Characteristics for All I/O Configurations

	Hot Swappable	Slew Rate Control	Power-Up Resistor		
TTL, LVTTL, LVCMOS2	Yes	Yes. Only affects falling edges of outputs	Pull-up or pull-down		
3.3 V PCI	No	No. High slew rate only	Pull-up or pull-down		
5 V PCI	Yes	No. High slew rate only	Pull-up or pull-down		

Table 1-4 • Power-Up Time at which I/Os Become Active

Supply Ramp Rate	0.25 V/ μs	0.025 V/ μs	5 V/ms	2.5 V/ms	0.5 V/ms	0.25 V/ms	0.1 V/ms	0.025 V/ms
Units	μs	μs	ms	ms	ms	ms	ms	ms
A54SX08A	10	96	0.34	0.65	2.7	5.4	12.9	50.8
A54SX16A	10	100	0.36	0.62	2.5	4.7	11.0	41.6
A54SX32A	10	100	0.46	0.74	2.8	5.2	12.1	47.2
A54SX72A	10	100	0.41	0.67	2.6	5.0	12.1	47.2



Design Environment

The SX-A family of FPGAs is fully supported by both Actel Libero[®] Integrated Design Environment (IDE) and Designer FPGA development software. Actel Libero IDE is design management environment. seamlessly а integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Additionally, Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Svnplify[®] for Actel from Synplicity[®], ViewDraw[®] for Actel from Mentor Graphics[®], ModelSim[®] HDL Simulator from Mentor Graphics, WaveFormer Lite™ from SynaptiCAD[™], and Designer software from Actel. Refer to the Libero IDE flow diagram for more information (located on the Actel website).

Actel Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can select and lock package pins while only minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators and the simulation results can be cross-probed with Silicon Explorer II, Actel's integrated verification and logic analysis tool. Another tool included in the Designer software is the SmarGen core generator, which easily creates popular and commonly used logic functions for implementation in your schematic or HDL design. Actel's Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys, and Cadence Design Systems. The Designer software is available for both the Windows and UNIX operating systems.

Programming

Device programming is supported through Silicon Sculptor series of programmers. In particular, Silicon Sculptor is compact, robust, single-site and multi-site device programmer for the PC.

With standalone software, Silicon Sculptor allows concurrent programming of multiple units from the same PC, ensuring the fastest programming times possible. Each fuse is subsequently verified by Silicon Sculptor II to insure correct programming. In addition, integrity tests ensure that no extra fuses are programmed. Silicon Sculptor also provides extensive hardware self-testing capability.

The procedure for programming an SX-A device using Silicon Sculptor is as follows:

- 1. Load the .AFM file
- 2. Select the device to be programmed
- 3. Begin programming

When the design is ready to go to production, Actel offers device volume-programming services either through distribution partners or via in-house programming from the factory.

For detailed information on programming, read the following documents *Programming Antifuse Devices* and *Silicon Sculptor User's Guide*.

Electrical Specifications

Table 2-5 • 3.3 V LVTTL and 5 V TTL Electrical Specifications

			Commercial		Indus	strial	
Symbol	Parameter		Min.	Max.	Min.	Max.	Units
V _{OH}	$V_{CCI} = Minimum$ $V_I = V_{IH} \text{ or } V_{IL}$	$(I_{OH} = -1 \text{ mA})$	0.9 V _{CCI}		0.9 V _{CCI}		V
	$V_{CCI} = Minimum$ $V_I = V_{IH} \text{ or } V_{IL}$	(I _{OH} = -8 mA)	2.4		2.4		V
V _{OL}	$V_{CCI} = Minimum$ $V_I = V_{IH} \text{ or } V_{IL}$	(I _{OL} = 1 mA)		0.4		0.4	V
	$V_{CCI} = Minimum$ $V_I = V_{IH} \text{ or } V_{IL}$	(I _{OL} = 12 mA)		0.4		0.4	V
V _{IL}	Input Low Voltage			0.8		0.8	V
V _{IH}	Input High Voltage		2.0	5.75	2.0	5.75	V
I _{IL} /I _{IH}	Input Leakage Current, V _{IN} = V _{CCI} or GND		-10	10	-10	10	μA
I _{OZ}	Tristate Output Leakage Current		-10	10	-10	10	μΑ
t _R , t _F	Input Transition Time t _R , t _F			10		10	ns
C _{IO}	I/O Capacitance			10		10	pF
I _{CC}	Standby Current			10		20	mA
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at http://www.actel.com/download/ibis/default.aspx.

Table 2-6 • 2.5 V LVCMOS2 Electrical Specifications

			Comn	nercial	Indu		
Symbol	Parameter		Min.	Max.	Min.	Max.	Units
V _{OH}	$V_{DD} = MIN,$	$(I_{OH} = -100 \ \mu A)$	2.1		2.1		V
	$V_{I} = V_{IH} \text{ or } V_{IL}$						
	$V_{DD} = MIN,$ $V_{I} = V_{UI}$ or V_{U}	$(I_{OH} = -1 \text{ mA})$	2.0		2.0		V
		(l - 2mA)	17		17		V
	$V_{DD} = V_{IH}$ or V_{IL}	(I _{OH} =2 IIIA)	1.7		1.7		v
V _{OL}	$V_{DD} = MIN,$	(I _{OL} = 100 μA)		0.2		0.2	V
	$V_{I} = V_{IH} \text{ or } V_{IL}$						
	$V_{DD} = MIN,$	(I _{OL} = 1 mA)		0.4		0.4	V
	$V_{I} = V_{IH} \text{ or } V_{IL}$	-					
	$V_{DD} = MIN,$	(I _{OL} = 2 mA)		0.7		0.7	V
	$V_{I} = V_{IH} \text{ or } V_{IL}$						
V _{IL}	Input Low Voltage, $V_{OUT} \le V_{VOL(max)}$		-0.3	0.7	-0.3	0.7	V
V _{IH}	Input High Voltage, $V_{OUT} \ge V_{VOH(min)}$		1.7	5.75	1.7	5.75	V
$I_{\rm IL}/I_{\rm IH}$	Input Leakage Current, V _{IN} = V _{CCI} or GND		-10	10	-10	10	μΑ
I _{OZ}	Tristate Output Leakage Current, $V_{OUT} = V_{CCI}$ or GND		-10	10	-10	10	μΑ
t _R , t _F	Input Transition Time t _R , t _F			10		10	ns
C _{IO}	I/O Capacitance			10		10	pF
I _{CC}	Standby Current			10		20	mA
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at http://www.actel.com/download/ibis/default.aspx.





Figure 2-2 shows the 3.3 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the SX-A family.

Figure 2-2 • 3.3 V PCI V/I Curve for SX-A Family

 $I_{OH} = (98.0/V_{CCI}) * (V_{OUT} - V_{CCI}) * (V_{OUT} + 0.4V_{CCI})$

for 0.7 $V_{CCI} < V_{OUT} < V_{CCI}$

 $I_{OL} = (256/V_{CCI}) * V_{OUT} * (V_{CCI} - V_{OUT})$ for 0V < V_{OUT} < 0.18 V_{CCI}

EQ 2-3

EQ 2-4

Power Dissipation

A critical element of system reliability is the ability of electronic devices to safely dissipate the heat generated during operation. The thermal characteristics of a circuit depend on the device and package used, the operating temperature, the operating current, and the system's ability to dissipate heat.

A complete power evaluation should be performed early in the design process to help identify potential heat-related problems in the system and to prevent the system from exceeding the device's maximum allowed junction temperature.

The actual power dissipated by most applications is significantly lower than the power the package can dissipate. However, a thermal analysis should be performed for all projects. To perform a power evaluation, follow these steps:

- 1. Estimate the power consumption of the application.
- 2. Calculate the maximum power allowed for the device and package.
- 3. Compare the estimated power and maximum power values.

Estimating Power Dissipation

The total power dissipation for the SX-A family is the sum of the DC power dissipation and the AC power dissipation:

$$P_{Total} = P_{DC} + P_{AC}$$

EQ 2-5

DC Power Dissipation

The power due to standby current is typically a small component of the overall power. An estimation of DC power dissipation under typical conditions is given by:

$$P_{DC} = I_{Standby} * V_{CCA}$$

EQ 2-6

Note: For other combinations of temperature and voltage settings, refer to the eX, SX-A and RT54SX-S Power Calculator.

AC Power Dissipation

The power dissipation of the SX-A family is usually dominated by the dynamic power dissipation. Dynamic power dissipation is a function of frequency, equivalent capacitance, and power supply voltage. The AC power dissipation is defined as follows:

$$P_{AC} = P_{C-cells} + P_{R-cells} + P_{CLKA} + P_{CLKB} + P_{HCLK} + P_{Output Buffer} + P_{Input Buffer}$$

EQ 2-7

or:

 $P_{AC} = V_{CCA}^{2} * [(m * C_{EQCM} * fm)_{C-cells} + (m * C_{EQSM} * fm)_{R-cells} + (n * C_{EQI} * f_{n})_{Input Buffer} + (p * (C_{EQO} + C_{L}) * f_{p})_{Output Buffer} + (0.5 * (q_{1} * C_{EQCR} * f_{q1}) + (r_{1} * f_{q1}))_{CLKA} + (0.5 * (q_{2} * C_{EQCR} * f_{q2}) + (r_{2} * f_{q2}))_{CLKB} + (0.5 * (s_{1} * C_{EQHV} * f_{s1}) + (C_{EQHF} * f_{s1}))_{HCLK}]$

EQ 2-8

Guidelines for Estimating Power

The following guidelines are meant to represent worst-case scenarios; they can be generally used to predict the upper limits of power dissipation:

Logic Modules (m) = 20% of modules Inputs Switching (n) = Number inputs/4 Outputs Switching (p) = Number of outputs/4 CLKA Loads (q1) = 20% of R-cells CLKB Loads (q2) = 20% of R-cells Load Capacitance (CL) = 35 pF Average Logic Module Switching Rate (fm) = f/10 Average Input Switching Rate (fn) = f/5 Average Output Switching Rate (fp) = f/10 Average CLKA Rate (fq1) = f/2 Average CLKB Rate (fq2) = f/2 Average HCLK Rate (fs1) = f HCLK loads (s1) = 20% of R-cells

To assist customers in estimating the power dissipations of their designs, Actel has published the eX, SX-A and RT54SX-S Power Calculator worksheet.



To determine the heat sink's thermal performance, use the following equation:

$$\theta_{JA(TOTAL)} = \theta_{JC} + \theta_{CS} + \theta_{SA}$$

EQ 2-14

where:

 $\theta_{CS} = 0.37^{\circ}C/W$

 thermal resistance of the interface material between the case and the heat sink, usually provided by the thermal interface manufacturer

 θ_{SA} = thermal resistance of the heat sink in °C/W

 $\theta_{SA} = \theta_{JA(TOTAL)} - \theta_{JC} - \theta_{CS}$ EQ 2-15 $\theta_{SA} = 13.33^{\circ}C/W - 3.20^{\circ}C/W - 0.37^{\circ}C/W$

$$\theta_{SA} = 9.76^{\circ}C/W$$

A heat sink with a thermal resistance of 9.76°C/W or better should be used. Thermal resistance of heat sinks is a function of airflow. The heat sink performance can be significantly improved with the presence of airflow.

Carefully estimating thermal resistance is important in the long-term reliability of an Actel FPGA. Design engineers should always correlate the power consumption of the device with the maximum allowable power dissipation of the package selected for that device, using the provided thermal resistance data.

Note: The values may vary depending on the application.



Timing Characteristics

Timing characteristics for SX-A devices fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all SX-A family members. Internal routing delays are device-dependent. Design dependency means actual delays are not determined until after placement and routing of the user's design are complete. The timing characteristics listed in this datasheet represent sample timing numbers of the SX-A devices. Design-specific delay values may be determined by using Timer or performing simulation after successful place-and-route with the Designer software.

Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing-critical paths. Critical nets are determined by net property assignment prior to placement and routing. Up to 6 percent of the nets in a design may be designated as critical, while 90 percent of the nets in a design are typical.

Long Tracks

Some nets in the design use long tracks. Long tracks are special routing resources that span multiple rows, columns, or modules. Long tracks employ three to five antifuse connections. This increases capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks contribute approximately 4 ns to 8.4 ns delay. This additional delay is represented statistically in higher fanout routing delays.

Timing Derating

SX-A devices are manufactured with a CMOS process. Therefore, device performance varies according to temperature, voltage, and process changes. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

Temperature and Voltage Derating Factors

 Table 2-13
 Temperature and Voltage Derating Factors

(Normalized to Worst-Case Commercial, T_J = 70°C, V_{CCA} = 2.25 V)

	Junction Temperature (T _J)												
V _{CCA}	–55°C	–40°C	0°C	25°C	70°C	85°C	125°C						
2.250 V	0.79	0.80	0.87	0.89	1.00	1.04	1.14						
2.500 V	0.74	0.75	0.82	0.83	0.94	0.97	1.07						
2.750 V	0.68	0.69	0.75	0.77	0.87	0.90	0.99						

Table 2-16 A54SX08A Timing Characteristics

(Worst-Case Commercial Conditions	V _{CCA} = 2.25 V, V _{CC}	₁ = 3.0 V, T _J = 70°C)
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		-2 S	peed	-1 S	peed	Std.	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated (H	lardwired) Array Clock Networks									
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.3		1.5		1.7		2.6	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.1		1.3		1.5		2.2	ns
t _{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{HPVVL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.4		0.5		0.5		0.8	ns
t _{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Arra	y Clock Networks									
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		0.8		0.9		1.1		1.5	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.2		1.4		2	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		0.8		0.9		1.1		1.5	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.2		1.4		2	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.2		1.4		1.9	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.2		1.3		1.6		2.2	ns
t _{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{RPVVL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.7		0.8		0.9		1.3	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.7		0.8		0.9		1.3	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.8		0.9		1.1		1.5	ns

Table 2-21 • A54SX16A Timing Characteristics

(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

		-3 Speed ¹ -2 Speed -1 Speed		peed	d Std. Speed			–F Speed				
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
C-Cell Propa	agation Delays ²											
t _{PD}	Internal Array Module		0.9		1.0		1.2		1.4		1.9	ns
Predicted R	outing Delays ³											
t _{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1		0.1	ns
t _{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.3		0.3		0.4		0.6	ns
t _{RD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.5		0.6	ns
t _{RD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t _{RD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t _{RD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1		1.4	ns
t _{RD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t _{RD12}	FO = 12 Routing Delay		1.7		2		2.2		2.6		3.6	ns
R-Cell Timin	ng											
t _{RCO}	Sequential Clock-to-Q		0.6		0.7		0.8		0.9		1.3	ns
t _{CLR}	Asynchronous Clear-to-Q		0.5		0.6		0.6		0.8		1.0	ns
t _{PRESET}	Asynchronous Preset-to-Q		0.7		0.8		0.8		1.0		1.4	ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.3		1.5		1.6		1.9		2.7		ns
t _{recasyn}	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t _{HASYN}	Asynchronous Removal Time	0.3		0.3		0.3		0.4		0.6		ns
t _{MPW}	Clock Minimum Pulse Width	1.4		1.7		1.9		2.2		3.0		ns
Input Modu	le Propagation Delays											
t _{INYH}	Input Data Pad to Y High 2.5 V LVCMOS		0.5		0.6		0.7		0.8		1.1	ns
t _{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS		0.8		0.9		1.0		1.1		1.6	ns
t _{INYH}	Input Data Pad to Y High 3.3 V PCI		0.5		0.6		0.6		0.7		1.0	ns
t _{INYL}	Input Data Pad to Y Low 3.3 V PCI		0.7		0.8		0.9		1.0		1.4	ns
t _{INYH}	lnput Data Pad to Y High 3.3 V LVTTL		0.7		0.7		0.8		1.0		1.4	ns
t _{INYL}	Input Data Pad to Y Low 3.3 V LVTTL		0.9		1.1		1.2		1.4		2.0	ns

Notes:

1. All –3 speed grades have been discontinued.

2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-37 • A54SX72A Timing Characteristics

(Worst-Case Commercial Conditions	5 V _{CCA} = 2.25 V, V _{CCI} = 3.0 V, T _J = 70	°C)
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		-3 Sp	-3 Speed*		peed	-1 S	peed	Std. Speed		-F Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated (Hardwired) Array Clock Netwo	rks										1
t _{нскн}	Input Low to High (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.8	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		1.9		2.1		2.5		3.8	ns
t _{HPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{HPVVL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{HCKSW}	Maximum Skew		1.4		1.6		1.8		2.1		3.3	ns
t _{HP}	Minimum Period	3.0		3.4		4.0		4.6		6.4		ns
f _{HMAX}	Maximum Frequency		333		294		250		217		156	MHz
Routed Arra	ay Clock Networks											
t _{rckh}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.6		2.9		3.4		4.8	ns
t _{rckl}	Input High to Low (Light Load) (Pad to R-cell Input)		2.8		3.3		3.7		4.3		6.0	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.4		2.8		3.2		3.7		5.2	ns
t _{rckl}	Input High to Low (50% Load) (Pad to R-cell Input)		2.9		3.4		3.8		4.5		6.2	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.6		3.0		3.4		4.0		5.6	ns
t _{rckl}	Input High to Low (100% Load) (Pad to R-cell Input)		3.1		3.6		4.1		4.8		6.7	ns
t _{RPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{RPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.9		2.2		2.5		3		4.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		1.9		2.1		2.4		2.8		3.9	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.9		2.1		2.4		2.8		3.9	ns
Quadrant A	rray Clock Networks											
t _{QCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.3		1.5		1.7		1.9		2.7	ns
t _{QCHKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.3		1.5		1.7		2		2.8	ns
t _{QCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.5		1.7		1.9		2.2		3.1	ns
t _{qchkl}	Input High to Low (50% Load) (Pad to R-cell Input)		1.5		1.8		2		2.3		3.2	ns

Note: *All –3 speed grades have been discontinued.

Table 2-41 • A54SX72A Timing Characteristics

(Worst-Case Commercial Condition	$V_{CCA} = 2.25 V, V_{CCI}$	= 4.75 V, T _J = 70°C)
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		–3 Sp	eed ¹	-2 S	peed	–1 Speed		Std. Speed		–F Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
5 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High		2.7		3.1		3.5		4.1		5.7	ns
t _{DHL}	Data-to-Pad High to Low		3.4		3.9		4.4		5.1		7.2	ns
t _{ENZL}	Enable-to-Pad, Z to L		1.3		1.5		1.7		2.0		2.8	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.7		3.1		3.5		4.1		5.7	ns
t _{ENLZ}	Enable-to-Pad, L to Z		3.0		3.5		3.9		4.6		6.4	ns
t _{ENHZ}	Enable-to-Pad, H to Z		3.4		3.9		4.4		5.1		7.2	ns
d _{TLH} ³	Delta Low to High		0.016		0.016		0.02		0.022		0.032	ns/pF
d _{THL} ³	Delta High to Low		0.026		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Out	put Module Timing ⁴											
t _{DLH}	Data-to-Pad Low to High		2.4		2.8		3.1		3.7		5.1	ns
t _{DHL}	Data-to-Pad High to Low		3.1		3.5		4.0		4.7		6.6	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		7.4		8.5		9.7		11.4		15.9	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.7		3.2		4.5	ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew		7.4		8.4		9.5		11.0		15.4	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.4		2.8		3.1		3.7		5.1	ns
t _{ENLZ}	Enable-to-Pad, L to Z		3.6		4.2		4.7		5.6		7.8	ns
t _{ENHZ}	Enable-to-Pad, H to Z		3.1		3.5		4.0		4.7		6.6	ns
d _{TLH} ³	Delta Low to High		0.014		0.017		0.017		0.023		0.031	ns/pF
d _{THL} ³	Delta High to Low		0.023		0.029		0.031		0.037		0.051	ns/pF
d _{THLS} ³	Delta High to Low—low slew		0.043		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. All –3 speed grades have been discontinued.

2. Delays based on 50 pF loading.

3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation: Slew Rate [V/ns] = (0.1* V_{CCI} – 0.9* V_{CCI} / (C_{load} * $d_{T[LH|HL|HLS]}$) where C_{load} is the load capacitance driven by the I/O in pF

 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

4. Delays based on 35 pF loading.



208-Pin PQFP					208-Pin PQFP					
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function	Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function	
71	I/O	I/O	I/O	I/O	106	NC	I/O	I/O	I/O	
72	I/O	I/O	I/O	I/O	107	I/O	I/O	I/O	I/O	
73	NC	I/O	I/O	I/O	108	NC	I/O	I/O	I/O	
74	I/O	I/O	I/O	QCLKA	109	I/O	I/O	I/O	I/O	
75	NC	I/O	I/O	I/O	110	I/O	I/O	I/O	I/O	
76	PRB, I/O	PRB, I/O	PRB, I/O	PRB,I/O	111	I/O	I/O	I/O	I/O	
77	GND	GND	GND	GND	112	I/O	I/O	I/O	I/O	
78	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}	113	I/O	I/O	I/O	I/O	
79	GND	GND	GND	GND	114	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}	
80	NC	NC	NC	NC	115	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}	
81	I/O	I/O	I/O	I/O	116	NC	I/O	I/O	GND	
82	HCLK	HCLK	HCLK	HCLK	117	I/O	I/O	I/O	V _{CCA}	
83	I/O	I/O	I/O	V _{CCI}	118	I/O	I/O	I/O	I/O	
84	I/O	I/O	I/O	QCLKB	119	NC	I/O	I/O	I/O	
85	NC	I/O	I/O	I/O	120	I/O	I/O	I/O	I/O	
86	I/O	I/O	I/O	I/O	121	I/O	I/O	I/O	I/O	
87	I/O	I/O	I/O	I/O	122	NC	I/O	I/O	I/O	
88	NC	I/O	I/O	I/O	123	I/O	I/O	I/O	I/O	
89	I/O	I/O	I/O	I/O	124	I/O	I/O	I/O	I/O	
90	I/O	I/O	I/O	I/O	125	NC	I/O	I/O	I/O	
91	NC	I/O	I/O	I/O	126	I/O	I/O	I/O	I/O	
92	I/O	I/O	I/O	I/O	127	I/O	I/O	I/O	I/O	
93	I/O	I/O	I/O	I/O	128	I/O	I/O	I/O	I/O	
94	NC	I/O	I/O	I/O	129	GND	GND	GND	GND	
95	I/O	I/O	I/O	I/O	130	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}	
96	I/O	I/O	I/O	I/O	131	GND	GND	GND	GND	
97	NC	I/O	I/O	I/O	132	NC	NC	NC	I/O	
98	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}	133	I/O	I/O	I/O	I/O	
99	I/O	I/O	I/O	I/O	134	I/O	I/O	I/O	I/O	
100	I/O	I/O	I/O	I/O	135	NC	I/O	I/O	I/O	
101	I/O	I/O	I/O	I/O	136	I/O	I/O	I/O	I/O	
102	I/O	I/O	I/O	I/O	137	I/O	I/O	I/O	I/O	
103	TDO, I/O	TDO, I/O	TDO, I/O	TDO, I/O	138	NC	I/O	I/O	I/O	
104	I/O	I/O	I/O	I/O	139	I/O	I/O	I/O	I/O	
105	GND	GND	GND	GND	140	I/O	I/O	I/O	I/O	



100-Pin TQFP



Figure 3-2 • 100-Pin TQFP

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.

	100-	TQFP			100-TQFP					
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function			
1	GND	GND	GND	36	GND	GND	GND			
2	TDI, I/O	TDI, I/O	TDI, I/O	37	NC	NC	NC			
3	I/O	I/O	I/O	38	I/O	I/O	I/O			
4	I/O	I/O	I/O	39	HCLK	HCLK	HCLK			
5	I/O	I/O	I/O	40	I/O	I/O	I/O			
6	I/O	I/O	I/O	41	I/O	I/O	I/O			
7	TMS	TMS	TMS	42	I/O	I/O	I/O			
8	V _{CCI}	V _{CCI}	V _{CCI}	43	I/O	I/O	I/O			
9	GND	GND	GND	44	V _{CCI}	V _{CCI}	V _{CCI}			
10	I/O	I/O	I/O	45	I/O	I/O	I/O			
11	I/O	I/O	I/O	46	I/O	I/O	I/O			
12	I/O	I/O	I/O	47	I/O	I/O	I/O			
13	I/O	I/O	I/O	48	I/O	I/O	I/O			
14	I/O	I/O	I/O	49	TDO, I/O	TDO, I/O	TDO, I/O			
15	I/O	I/O	I/O	50	I/O	I/O	I/O			
16	TRST, I/O	trst, I/O	trst, I/O	51	GND	GND	GND			
17	I/O	I/O	I/O	52	I/O	I/O	I/O			
18	I/O	I/O	I/O	53	I/O	I/O	I/O			
19	I/O	I/O	I/O	54	I/O	I/O	I/O			
20	V _{CCI}	V _{CCI}	V _{CCI}	55	I/O	I/O	I/O			
21	I/O	I/O	I/O	56	I/O	I/O	I/O			
22	I/O	I/O	I/O	57	V _{CCA}	V _{CCA}	V _{CCA}			
23	I/O	I/O	I/O	58	V _{CCI}	V _{CCI}	V _{CCI}			
24	I/O	I/O	I/O	59	I/O	I/O	I/O			
25	I/O	I/O	I/O	60	I/O	I/O	I/O			
26	I/O	I/O	I/O	61	I/O	I/O	I/O			
27	I/O	I/O	I/O	62	I/O	I/O	I/O			
28	I/O	I/O	I/O	63	I/O	I/O	I/O			
29	I/O	I/O	I/O	64	I/O	I/O	I/O			
30	I/O	I/O	I/O	65	I/O	I/O	I/O			
31	I/O	I/O	I/O	66	I/O	I/O	I/O			
32	I/O	I/O	I/O	67	V _{CCA}	V _{CCA}	V _{CCA}			
33	I/O	I/O	I/O	68	GND	GND	GND			
34	PRB, I/O	PRB, I/O	PRB, I/O	69	GND	GND	GND			
35	V _{CCA}	V _{CCA}	V _{CCA}	70	I/O	I/O	I/O			

144-Pin TQFP



Figure 3-3 • 144-Pin TQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.



176-Pin TQFP						
Pin Number	A54SX32A Function					
145	I/O					
146	I/O					
147	I/O					
148	I/O					
149	I/O					
150	I/O					
151	I/O					
152	CLKA					
153	CLKB					
154	NC					
155	GND					
156	V _{CCA}					
157	PRA, I/O					
158	I/O					
159	I/O					
160	I/O					
161	I/O					
162	I/O					
163	I/O					
164	I/O					
165	I/O					
166	I/O					
167	I/O					
168	I/O					
169	V _{CCI}					
170	I/O					
171	I/O					
172	I/O					
173	I/O					
174	I/O					
175	I/O					
176	TCK, I/O					

Previous Version	Changes in Current Version (v5.3)	Page				
v4.0	Table 2-12 was updated.	2-11				
(continued)	The was updated.	2-14				
	The "Sample Path Calculations" were updated.					
	Table 2-13 was updated.	2-17				
	Table 2-13 was updated.	2-17				
	All timing tables were updated.	2-18 to 2-52				
v3.0	The "Actel Secure Programming Technology with FuseLock™ Prevents Reverse Engineering and Design Theft" section was updated.	1-i				
	The "Ordering Information" section was updated.	1-ii				
	The "Temperature Grade Offering" section was updated.	1-iii				
	The Figure 1-1 • SX-A Family Interconnect Elements was updated.	1-1				
	The ""Clock Resources" section" was updated	1-5				
	The Table 1-1 • SX-A Clock Resources is new.	1-5				
	The "User Security" section is new.	1-7				
	The "I/O Modules" section was updated.	1-7				
	The Table 1-2 • I/O Features was updated.	1-8				
	The Table 1-3 • I/O Characteristics for All I/O Configurations is new.	1-8				
	The Table 1-4 • Power-Up Time at which I/Os Become Active is new	1-8				
	The Figure 1-12 • Device Selection Wizard is new.	1-9				
	The "Boundary-Scan Pin Configurations and Functions" section is new.	1-9				
	The Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved) is new.	1-11				
	The "SX-A Probe Circuit Control Pins" section was updated.	1-12				
	The "Design Considerations" section was updated.	1-12				
	The Figure 1-13 • Probe Setup was updated.	1-12				
	The Design Environment was updated.	1-13				
	The Figure 1-13 • Design Flow is new.	1-11				
	The "Absolute Maximum Ratings*" section was updated.	1-12				
	The "Recommended Operating Conditions" section was updated.	1-12				
	The "Electrical Specifications" section was updated.	1-12				
	The "2.5V LVCMOS2 Electrical Specifications" section was updated.	1-13				
	The "SX-A Timing Model" and "Sample Path Calculations" equations were updated.	1-23				
	The "Pin Description" section was updated.	1-15				
v2.0.1	The "Design Environment" section has been updated.	1-13				
	The "I/O Modules" section, and Table 1-2 • I/O Features have been updated.	1-8				
	The "SX-A Timing Model" section and the "Timing Characteristics" section have new timing numbers.	1-23				

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